

Notice of References Cited	Application/Control No. 10/661,116	Applicant(s)/Patent Under Reexamination PUTNAM ET AL.	
	Examiner Arnel C. Lavarias	Art Unit 2872	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-5,745,615	04-1998	Atkins et al.	385/37
	C	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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NON-PATENT DOCUMENTS

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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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